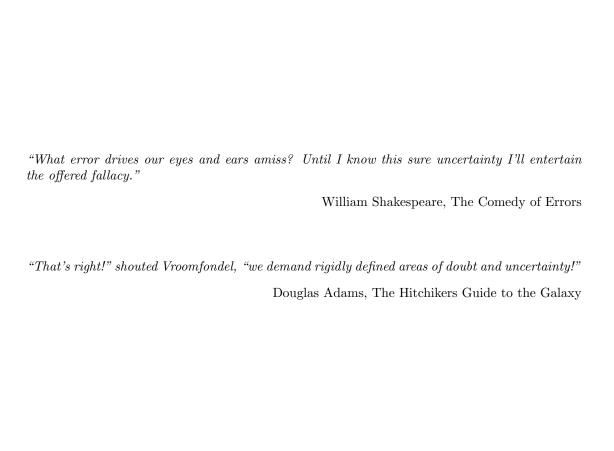
Declaration of Authorship

Laurence Stant (Author)

I confirm that the submitted work is my own work and that I have clearly identified and fully acknowledged all material that is entitled to be attributed to others (whether published or unpublished) using the referencing system set out in the programme handbook. I agree that the University may submit my work to means of checking this, such as the plagiarism detection service Turnitin UK. I confirm that I understand that assessed work that has been shown to have been plagiarised will be penalised.

The authors confirm that data underlying the findings are available without restriction. Details of the data and how to request access are available from the University of Surrey publications repository at http://epubs.surrey.ac.uk/blahTBD

Date



Abstract

Abstract goes here

Research Outcomes

Publications

- H. Votsi, L. Stant, N. Ridler, and P. Aaen, "Uncertainty evaluation of an active interferometric method for measuring extreme impedance on-wafer devices," *IEEE Transactions on Microwave Theory and Techniques*, 2018.
- [2] L. Stant, D. Root, N. Ridler, and P. Aaen, "Uncertainty evaluation of predicted optimum load match using x-parameters of microwave amplifiers," *IEEE Microwave and Wireless Components Letters*, 2018.
- [3] L. Stant, M. Salter, N. Ridler, D. Williams, and P. Aaen, "Propagating measurement uncertainty to microwave amplifier nonlinear behavioural models," *IEEE Transactions on Microwave Theory and Techniques*, 2018.
- [4] L. Stant, P. Aaen, and N. Ridler, "Evaluating residual errors in waveguide VNAs from microwave to submillimetre-wave frequencies," *IET Microwaves, Antennas & Propagation*, vol. 11, no. 3, pp. 324–329, Feb. 2017. DOI: 10.1049/iet-map.2016.0455.
- [5] —, "Comparing methods for evaluating measurement uncertainty given in the JCGM 'evaluation of measurement data' documents," *Measurement*, vol. 94, pp. 847–851, Dec. 2016. DOI: 10.1016/j.measurement.2016.08.015.
- [6] —, "Evaluating residual errors in waveguide network analysers from microwave to submillimetre-wave frequencies," in IET Colloquium on Millimetre-Wave and Terahertz Engineering [amp] Technology 2016, Institution of Engineering and Technology (IET), 2016. DOI: 10.1049/ic.2016.0016.

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